

DUAL VIEW ICP-OES MINUS THE COMPROMISE

Agilent 5110 ICP-OES



THE FASTEST, MOST PRECISE ICP-OES... EVER.

Agilent's 5110 Synchronous Vertical Dual View (SVDV) ICP-OES combines speed and analytical performance, so you don't have to compromise on either.

Uncompromised speed

- Run the fastest ICP-OES analysis, using less gas.
- Reduce your cost-per-analysis and more than double your productivity with an Advanced Valve System (AVS).
- Measure all wavelengths in one measurement, for higher precision without delays.
- Start work sooner with the zero gas consumption VistaChip II detector that shortens warm-up time.

Uncompromised performance

- Measure your toughest samples with a vertical torch.
- Achieve long term analytical stability with a solid-state RF system.

Uncompromised ease of use

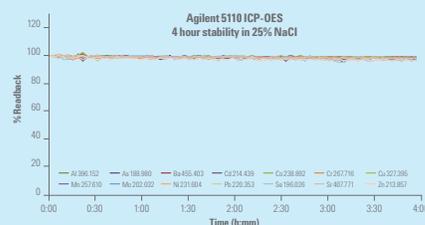
- See all elements in your sample at a glance in IntelliQuant mode.
- Take the guess work out of method development with intuitive ICP Expert software and DSC technology.
- Ensure fast startup with minimal training using a fully integrated switching valve and a plug-and-play torch.
- Maximize instrument uptime with smart diagnostics software that makes troubleshooting simple.

Flexible Configurations

The Agilent 5110 is available in three configurations:

- Synchronous Vertical Dual View
- Vertical Dual View
- Radial View

With a vertical torch and robust solid state RF in every configuration, the 5110 ICP-OES handles your toughest samples with ease.



Shown is the percentage readback on a range of elements in a 25% NaCl solution. Readback stability for all elements over 4 hours was < 1.3% RSD, without internal standardization.



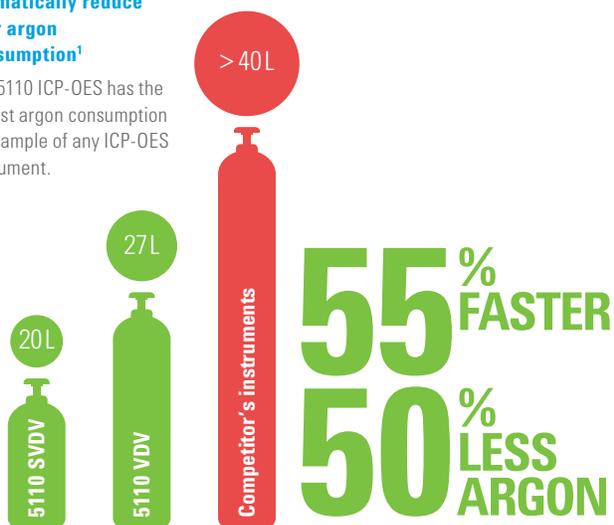
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How does Synchronous Vertical Dual View work?

The 5110 SVDV ICP-OES needs only a single measurement per sample. The Dichroic Spectral Combiner allows both the axial and radial views of the plasma to be captured in one reading. This delivers accurate results in the quickest possible time¹.

Dramatically reduce your argon consumption¹

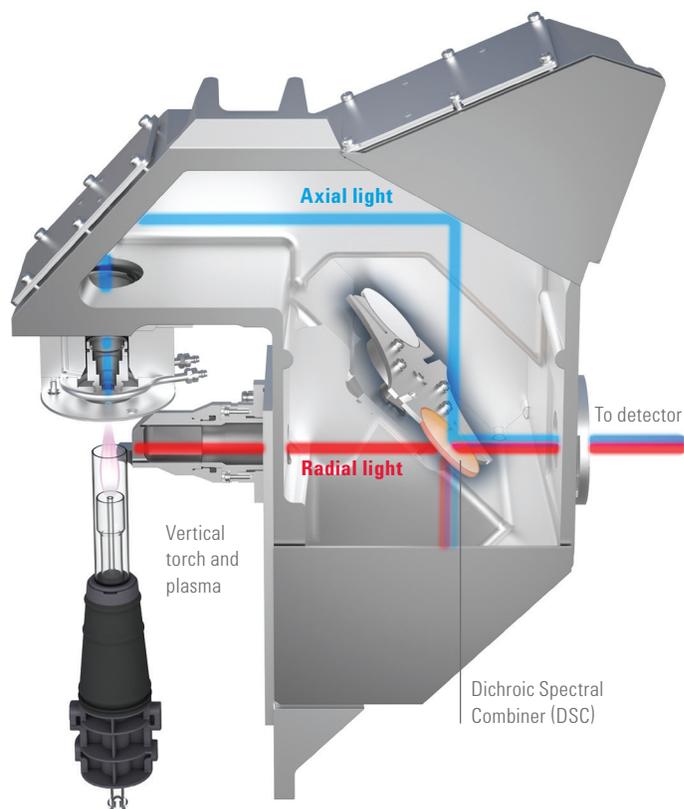
The 5110 ICP-OES has the lowest argon consumption per sample of any ICP-OES instrument.



Did you know?

Conventional dual view ICP-OES systems require you to set up a series of sequential measurements by selecting which elements are measured in axial mode and which are measured in radial mode.

Some systems also use two slits to measure low and high wavelengths in each mode, resulting in up to four sequential measurements on each sample, making sample throughput slow.



1. The analysis speed and gas consumption figures are compared to competitive systems, based on published application data. Refer to Agilent application note 5991-4821EN

For more information:
Contact your local Agilent
representative or visit:
www.agilent.com/chem/5110icpoes

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